

MM54HC266A/MM74HC266A Quad 2-Input Exclusive NOR Gate (Open Drain)

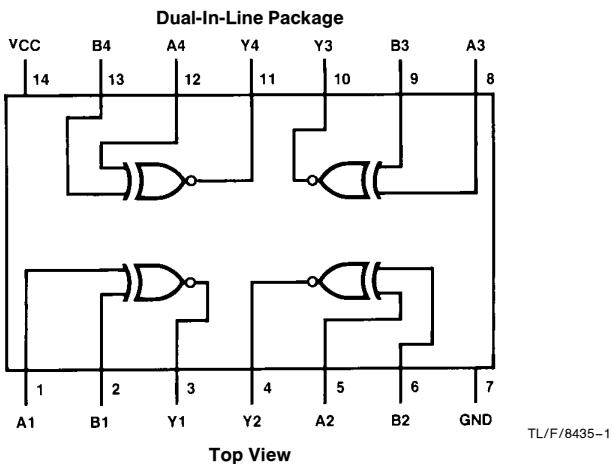
General Description

This exclusive NOR gate utilizes advanced silicon-gate CMOS technology to achieve operating speeds similar to equivalent LS-TTL gates while maintaining the low power consumption and high noise immunity characteristic of standard CMOS integrated circuits. These gates are fully buffered and have a fanout of 10 LS-TTL loads. The MM54HC/MM74HC logic family is functionally as well as pin out compatible with the standard 54LS/74LS logic family. All inputs are protected from damage due to static discharge by internal diode clamps to V_{CC} and ground.

Features

- Typical propagation delay: 9 ns
- Wide operating voltage range: 2–6V
- Low input current: 1 μ A maximum
- Low quiescent current: 20 μ A maximum (74 Series)
- Output drive capability: 10 LS-TTL loads
- Open drain outputs

Connection Diagram



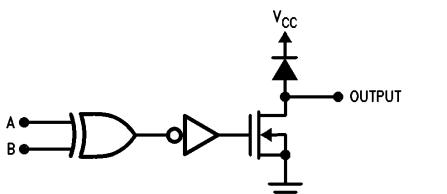
Order Number **MM54HC266A or MM74HC266A**

Truth Table

Inputs		Outputs Y
A	B	
L	L	Z
L	H	L
H	L	L
H	H	Z

$$Y = \overline{A} \oplus \overline{B} = AB + \overline{AB}$$

Logic Diagram



TL/F/8435-2

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Absolute Maximum Ratings (Notes 1 & 2)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Supply Voltage (V_{CC})	-0.5 to $+7.0$ V
DC Input Voltage (V_{IN})	-1.5 to $V_{CC} + 1.5$ V
DC Output Voltage (V_{OUT})	-0.5 to $V_{CC} + 0.5$ V
Clamp Diode Current (I_{IK}, I_{OK})	± 20 mA
DC Output Current, per pin (I_{OUT})	± 25 mA
DC V_{CC} or GND Current, per pin (I_{CC})	± 50 mA
Storage Temperature Range (T_{STG})	-65°C to $+150^{\circ}\text{C}$
Power Dissipation (P_D) (Note 3)	600 mW
S.O. Package only	500 mW
Lead Temp. (T_L) (Soldering 10 seconds)	260°C

Operating Conditions

	Min	Max	Units
Supply Voltage (V_{CC})	2	6	V
DC Input or Output Voltage (V_{IN}, V_{OUT})	0	V_{CC}	V
Operating Temp. Range (T_A) MM74HC	-40	$+85$	°C
MM54HC	-55	$+125$	°C
Input Rise or Fall Times (t_r, t_f)			
$V_{CC} = 2.0$ V	1000	ns	
$V_{CC} = 4.5$ V	500	ns	
$V_{CC} = 6.0$ V	400	ns	

DC Electrical Characteristics (Note 4)

Symbol	Parameter	Conditions	V_{CC}	$T_A = 25^{\circ}\text{C}$		74HC	54HC	Units
				Typ	Guaranteed Limits			
V_{IH}	Minimum High Level Input Voltage		2.0V 4.5V 6.0V	1.5 3.15 4.2	1.5 3.15 4.2	1.5 3.15 4.2	1.5 3.15 4.2	V
V_{IL}	Maximum Low Level Input Voltage**		2.0V 4.5V 6.0V	0.5 1.35 1.8	0.5 1.35 1.8	0.5 1.35 1.8	0.5 1.35 1.8	V
V_{OH}	Minimum High Level Output Voltage $V_{IN} = V_{IH}$ or V_{IL} $ I_{OUT} \leq 20 \mu\text{A}$		2.0V 4.5V 6.0V	2.0 4.5 6.0	1.9 4.4 5.9	1.9 4.4 5.9	1.9 4.4 5.9	V
	$V_{IN} = V_{IL}$ $ I_{OUT} \leq 4.0 \text{ mA}$ $ I_{OUT} \leq 5.2 \text{ mA}$		4.5V 6.0V	4.2 5.7	3.98 5.48	3.84 5.34	3.7 5.2	V
V_{OL}	Maximum Low Level Output Voltage $V_{IN} = V_{IH}$ or V_{IL} $ I_{OUT} \leq 20 \mu\text{A}$		2.0V 4.5V 6.0V	0 0 0	0.1 0.1 0.1	0.1 0.1 0.1	0.1 0.1 0.1	V
	$V_{IN} = V_{IH}$ or V_{IL} $ I_{OUT} \leq 4.0 \text{ mA}$ $ I_{OUT} \leq 5.2 \text{ mA}$		4.5V 6.0V	0.2 0.2	0.26 0.26	0.33 0.33	0.4 0.4	V
I_{IN}	Maximum Input Current	$V_{IN} = V_{CC}$ or GND	6.0V		± 0.1	± 1.0	± 1.0	μA
I_{CC}	Maximum Quiescent Supply Current	$V_{IN} = V_{CC}$ or GND $I_{OUT} = 0 \mu\text{A}$	6.0V		2.0	20	40	μA
I_{OZ}	Maximum TRI-STATE® Leakage Current	$V_{IN} = V_{IL}$ or V_{IH} $V_{OUT} = V_{CC}$ or GND	6.0V		± 0.5	± 5.0	± 10.0	μA

Note 1: Absolute Maximum Ratings are those values beyond which damage to the device may occur.

Note 2: Unless otherwise specified all voltages are referenced to ground.

Note 3: Power Dissipation temperature derating — plastic "N" package: $-12 \text{ mW}/^{\circ}\text{C}$ from 65°C to 85°C ; ceramic "J" package: $-12 \text{ mW}/^{\circ}\text{C}$ from 100°C to 125°C .

Note 4: For a power supply of $5V \pm 10\%$ the worst case output voltages (V_{OH} and V_{OL}) occur for HC at 4.5V. Thus the 4.5V values should be used when designing with this supply. Worst case V_{IH} and V_{IL} occur at $V_{CC} = 5.5$ V and 4.5V respectively. (The V_{IH} value at 5.5V is 3.85V.) The worst case leakage current (I_{IN} , I_{CC} , and I_{OZ}) occur for CMOS at the higher voltage and so the 6.0V values should be used.

** V_{IL} limits are currently tested at 20% of V_{CC} . The above V_{IL} specification (30% of V_{CC}) will be implemented no later than Q1, CY'89.

AC Electrical Characteristics $V_{CC} = 5V$, $T_A = 25^\circ C$, $C_L = 15 pF$, $t_r = t_f = 6 ns$

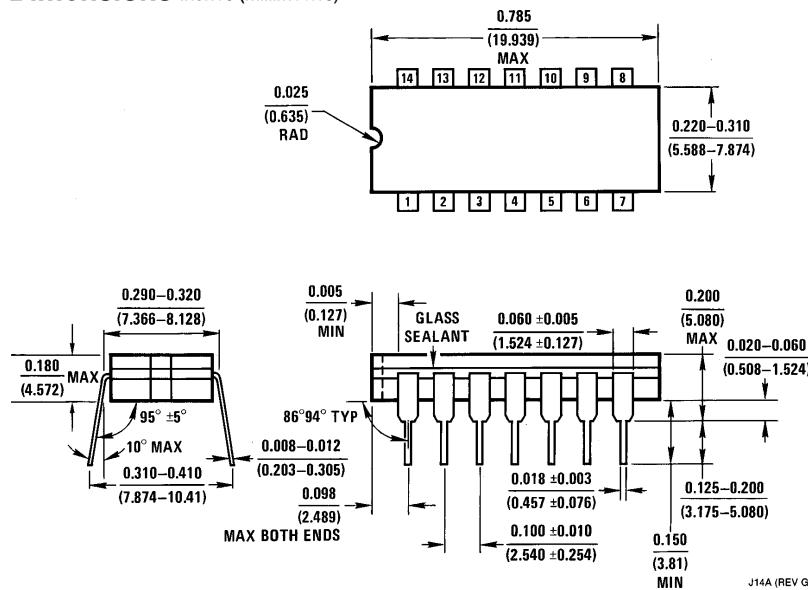
Symbol	Parameter	Conditions	Typ	Guaranteed Limit	Units
t_{PLZ}, t_{PZL}	Maximum Propagation Delay		12	20	ns

AC Electrical Characteristics $V_{CC} = 2.0V$ to $6.0V$, $C_L = 50 pF$, $t_r = t_f = 6 ns$ (unless otherwise specified)

Symbol	Parameter	Conditions	V_{CC}	$T_A = 25^\circ C$		$74HC$	$54HC$	Units
				Typ	Guaranteed Limits			
t_{PLZ}, t_{PZL}	Maximum Propagation Delay		2.0V 4.5V 6.0V	60 12 10	120 24 20	151 30 26	179 36 30	ns ns ns
t_{THL}	Maximum Output Fall Time		2.0V 4.5V 6.0V	30 8 7	75 15 13	95 19 16	110 22 19	ns ns ns
C_{PD}	Power Dissipation Capacitance (Note 5)	(per gate)		25				pF
C_{IN}	Maximum Input Capacitance			5	10	10	10	pF
C_{OUT}	Maximum Three State Output Capacitance Output in TRI-STATE				10	10	10	pF

Note 5: C_{PD} determines the no load dynamic power consumption, $P_D = C_{PD} V_{CC}^2 f + I_{CC} V_{CC}$, and the no load dynamic current consumption, $I_S = C_{PD} V_{CC} f + I_{CC}$.

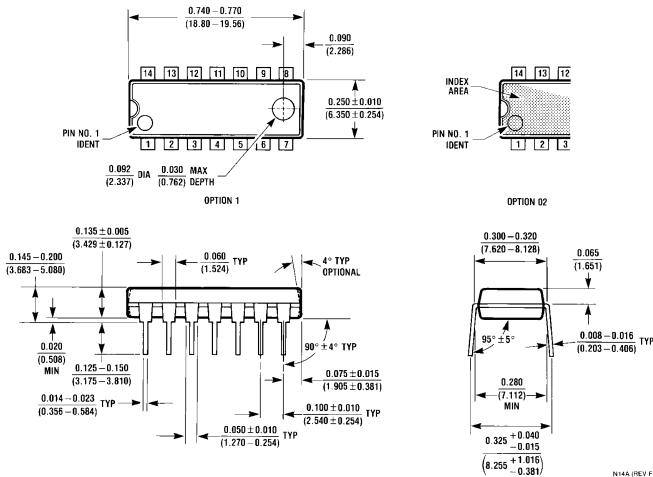
Physical Dimensions inches (millimeters)



Ceramic Dual-In-Line Package (J)
Order Number MM54HC266AJ
NS Package Number J14A

MM54HC266A/MM74HC266A Quad 2-Input Exclusive NOR Gate (Open Drain)

Physical Dimensions inches (millimeters) (Continued)



**Molded Dual-In-Line Package (N)
Order Number MM74HC266AN
NS Package Number N14A**

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